

Resource Summary Report

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Filmetrics F20 Thin Film Measurement System

RRID:SCR_028212

Type: Tool

Proper Citation

Filmetrics F20 Thin Film Measurement System (RRID:SCR_028212)

Resource Information

URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_028212.pdf

Proper Citation: Filmetrics F20 Thin Film Measurement System (RRID:SCR_028212)

Description: Filmetrics F20 is a versatile, benchtop thin-film measurement system designed to measure the thickness, refractive index, and extinction coefficient of thin films. Using spectral reflectance in less than a second, it measures single or multi-layer stacks.

Synonyms: , Filmetrics F20 Thin-Film Analyzer

Resource Type: instrument resource

Keywords: benchtop thin-film measurement system, measure thickness, refractive index, extinction coefficient, thin films,

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Resource Name: Filmetrics F20 Thin Film Measurement System

Resource ID: SCR_028212

Alternate IDs: Model_Number_Filmetrics_F20

Record Creation Time: 20260327T054534+0000

Record Last Update: 20260912T200545+0000

Ratings and Alerts

No rating or validation information has been found for Filmetrics F20 Thin Film Measurement System.

No alerts have been found for Filmetrics F20 Thin Film Measurement System.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.